

**Search Notes**

Application/Control No.

10/795,777

Examiner

Sheela C. Chawan

Applicant(s)/Patent under  
Reexamination

JEONG ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
382	154	12/7/2006	SCC
348	42	12/7/2006	"
	135	12/7/2006	"
345	419	12/7/2006	"
396	324	12/7/2006	"
352	57,86	12/7/2006	"
359	462	12/7/2006	"
ABOVE	SEARCH	12/7/2006	"
UP-DAT.			

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
382	154	12/7/2006	SCC
348	42,135	12/7/2006	"
352	57,86	12/7/2006	"
359/462		12/7/2006	"

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, US- PGPUB,USPAT,EPO,JPO,DERWENT ,IBM-TDB.	12/7/2006	SCC
382/154,107.CCLS. 348/42,135,323,321.CCLS. 345/419.CCLS. 396/324.CCLS. 352/57,86.CCLS. 359/462.CCLS. US-PATENT TEXT SEARCH.	12/7/2006	"
INVENTOR NAME SEARCH.	12/7/2006	"
INTERFERENCE SEARCH.	12/7/2006	"
IEEE OR INSPEC SEARCH.	12/7/2006	"
ABOVE SEARCH UP-DATE.	12/7/2006	"